Secure Integration of IoT & Digital Twins

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Message from the Guest Editors

Dear Colleagues,

Digital Twin is a recently developed technique that offers more reliable results for novel and demanding systems. The Digital Twins concept is most frequently used to better "predict" functionality through a virtual model designed to accurately reflect a physical object. Through such a system, useful information could be extracted about its reliability and its usage, as well as the degree of improvement of the existing system/object.

The topics of interest include but are not limited to the following:

Integration benefits of the Internet of Things and Digital Twins;
Security challenges of a Digital Twin system of IoT-based cloud;
Big Data secure management through a Digital Twin system;
Secure machine learning IoT-based Big Data analytics in the cloud;
Challenges and applications of IoT-based Big Data in Digital Twins;
Security and privacy issues in Internet-of-Things-enabled systems in a Digital Twin scenario.

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Special Issue

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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